

Method for testing the brain

Hinrikus, Hiie; Bachmann, Maie; Lass, Jaanus; Tuulik, Viiu; Ubar, Raimund-Johannes 5th European Conference of the International Federation for Medical and Biological Engineering : 14-18 September 2011, Budapest, Hungary 2012 / p. 1198-1201 : ill

On BTI aging rejuvenation in memory address decoders

Gürsoy, Cemil Cem; Kraak, Daniel; Ahmed, Faisal; Taouil, Mottaqiallah; Jenihhin, Maksim; Hamdioui, Said 2022 IEEE 23rd Latin American Test Symposium, LATS 2022 2022 / Code 184360 <https://doi.org/10.1109/LATS57337.2022.9936940>

Software-based mitigation for memory address decoder aging

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